| | | <u>~</u> |
|--|--|---|
| Application No. | Applicant(s) | |
| 10/670,738 | PARK ET AL. | |
| Examiner | Art Unit | |
| Thoi V. Duong | 2871 | |
| The MAILING DATE of this communication appears on the cover sheet with the correspondence address All claims being allowable, PROSECUTION ON THE MERITS IS (OR REMAINS) CLOSED in this application. If not included herewith (or previously mailed), a Notice of Allowance (PTOL-85) or other appropriate communication will be mailed in due course. THIS NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIGHTS. This application is subject to withdrawal from issue at the initiative of the Office or upon petition by the applicant. See 37 CFR 1.313 and MPEP 1308. | | |
| 1. ☑ This communication is responsive to the RCE filed February 08, 2006. | | |
| 2. The allowed claim(s) ie/are 1-26. | | |
| 3. | | |
| 6. ☐ Interview Summary Paper No./Mail Dat 8), 7. ☒ Examiner's Amendr | (PTO-413), e nent/Comment | |
| | Thoi V. Duong ars on the cover sheet with the coordinate communication of the appropriate communication of the second of the se | Examiner Thoi V. Duong 2871 Art Unit Thoi V. Duong 2871 Ars on the cover sheet with the correspondence addroor other appropriate communication will be mailed in due GHTS. This application is subject to withdrawal from issuand MPEP 1308. y. 08, 2006. der 35 U.S.C. § 119(a)-(d) or (f). been received. been received in Application No uments have been received in this national stage application of this application. tted. Note the attached EXAMINER'S AMENDMENT or No is reason(s) why the oath or declaration is deficient. to be submitted. On's Patent Drawing Review (PTO-948) attached Amendment / Comment or in the Office action of 84(c)) should be written on the drawings in the front (not the leader according to 37 CFR 1.121(d). Sit of BIOLOGICAL MATERIAL must be submitted. If OR THE DEPOSIT OF BIOLOGICAL MATERIAL. 5 Notice of Informal Patent Application (PTO-948) attached. Interview Summary (PTO-9413), Paper No./Mail Date 7 Examiner's Amendment/Comment 8 Examiner's Statement of Reasons for Allocation |

Application/Control Number: 10/670,738 Page 2

Art Unit: 2871

DETAILED ACTION

Continued Examination Under 37 CFR 1.114

1. A request for continued examination under 37 CFR 1.114, including the fee set forth in 37 CFR 1.17(e), was filed in this application after final rejection. Since this application is eligible for continued examination under 37 CFR 1.114, and the fee set forth in 37 CFR 1.17(e) has been timely paid, the finality of the previous Office action has been withdrawn pursuant to 37 CFR 1.114. Applicant's submission filed on February 08, 2006 has been entered.

Accordingly, claims 1-4, 10, 11, 16 and 17 were amended, and new claims 18-26 were added. Currently, claims 1-26 are pending in this application.

EXAMINER'S AMENDMENT

2. An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

Authorization for this examiner's amendment was given in a telephone interview with David B. Hardy (Reg. No. 47,362) on April 10, 2006.

In the claims:

<u>Claim 11</u>: in line 13, after "portions of the" delete "second" and insert --second--in front of "portions of the".

Allowable Subject Matter

3. Claims 1-26 are allowed.

Application/Control Number: 10/670,738

Art Unit: 2871

The following is an examiner's statement of reasons for allowance: none of the prior art of record fairly suggests or shows all of the limitations as claimed. Specifically,

Re claims 1, 4, 11 and 16, none of the prior art of record discloses, in combination with other limitations as claimed, a data pad region of a liquid crystal display panel as well as a method for fabricating the same comprising including a first contact area having a plurality of first contact regions exposing first side portions of the data line and first portions of the gate insulating layer, a second contact area having a plurality of second contact regions exposing second side portions of the data line and second portions of the gate insulating layer, and a central contact area disposed between the first and second contact areas and exposing a third portion of the gate insulating layer; and

a conductive material disposed within each of the first, second and central contact areas and continuously contacting each of the first and second side portions of the data line and the first and second portions of the gate insulating layer exposed in the first and second contact regions, respectively, and the third portion of the gate insulating layer,

wherein a contact area of the conductive material and the third portion of the gate insulating laver is greater than each contact area of the conductive material and the first and second portions of the gate insulating layer.

The most relevant reference, USPN 6,642,972 B2 to Yoo et al. (Yoo), fails to disclose or suggest second side portions of the data line exposed in a second contact area having a plurality of second contact regions.

As shown in Fig. 8C, Yoo discloses a data pad region a first contact area 139 having a plurality of first contact regions exposing first side portions of the data line 115 and first portions of the gate insulating layer 131, a second contact area 149 having a plurality of second contact regions exposing second portions of the gate insulating layer 131, and a central contact area 150 disposed between the first and second contact areas 139 and 149 and exposing a third portion of the gate insulating layer 131; and, as shown in Fig. 8D, a conductive material 143 disposed within each of the first, second and central contact areas and continuously contacting the first side portions of the data line 115 and the first and second portions of the gate insulating layer 131 exposed in the first and second contact regions, respectively, and the third portion of the gate insulating layer,

wherein a contact area of the conductive material 143 and the third portion of the gate insulating layer 131 is greater than each contact area of the conductive material 143 and the first and second portions of the gate insulating layer 131 as shown in Fig. 8D.

However, Fig. 8D of Yoo does not show that the conductive material 143 contacts the second side portions of the data line 115 in the second contact area 149 since the second side portions of the data line 115 are not exposed in the second contact area 149.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably Application/Control Number: 10/670,738 Page 5

Art Unit: 2871

accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Conclusion

4. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Thoi V. Duong whose telephone number is (571) 272-2292. The examiner can normally be reached on Monday-Friday from 8:30 am to 4:30 pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Robert Kim, can be reached at (571) 272-2293.

Thoi Duong

Jud

04/10/2006

DUNGT. NGUYEN PRIMARY EXAMINER